



# Non-Invasive Transverse Profile Measurement Methods

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#### Introduction

- Non-Invasive
	- No significant alteration of the beam phase space or intensity
	- No damage to the instrument
- No synchrotron radiation (only exists in LHC now?)
- Interaction of the beam with a gas
	- Either via ionization or fluorescence
	- Using either residual or injected gas
- Electron/ion probe beams
- Laser-induced photoionization (unique for H-)





## Residual Gas Ionization

• Utilize beam-induced ionization of residual gas in the beampipe  $N_2 + p \rightarrow N_2^+ + e^- + p$ 







## Residual Gas Ionization

- Use an electric field to separate the ionization products
	- Typically in a range of 100 300 kV/m

Typically called an Ionization Profile Monitor, IPM (but also RGM, BGI, …)

- Want to preserve ion/electron starting positions during trip to detector
	- Trajectories may be impacted by space charge of the beam *V. Shiltsev, NIMA 986 (2021) 164744*
- Can use a magnetic field parallel to electric field to constrain electron trajectories if collecting electrons







Better **spatial** resolution

beam

Better **time** resolution

#### IPM – Signal collection

- Signal is typically small A few per bunch to hundreds per bunch
	- Requires low-noise amplification or low-noise data acquisition
- Microchannel Plate  $\rightarrow$  Phosphor Screen  $\rightarrow$  Imaging System
- Phosphor Screen  $\rightarrow$  Intensified Imaging System
	- Microchannel plates are outside the vacuum
- Microchannel Plate  $\rightarrow$  Copper Strips or Wires  $\rightarrow$  Data Acquisition









## IPM – Signal collection







#### IPM – Signal collection

#### **MCP / Conductive Strips**



*All electron collection with magnet*

*FNAL MI/RR* ∼1 MHz Bandwidth 2.5 mm







#### *R. Connolly et al., BNL-102439-2013-TECH*





MCP / Strips Conductive Strips 0.5 mm pitch

MARK II IPM ANCOE<br>STRIP BOARD<br>0880-EC-417150 SCH





#### Microchannel Plate Features

- Short-term drop in gain for large current draw
	- **O**(1 ms) charging time
- Gradual drop in gain due to aging
	- Function of current drawn from the MCP (>1 C/cm<sup>2</sup>)
- Fast initial gain drop due to 'scrubbing'
	- Adsorbed gasses must be removed after exposure to air







#### *K. Satou, 3rd IPM Workshop*



Calibrate gain: UV lamp, step the beam





#### Gating the IPM

#### • Include an additional electrode in the path of the detected particles







**Ionization**

# IPM – Signal collection

#### *S. Levasseur et al., IBIC2021 J. Storey, 20th Anniversary Timepix Symposium; BI Day 2017*

Electron collection



Timepix3 characteristics:

Performance limitations:

**• Detector resolution = 55 µm**

• Dead time per pixel > 475 ns

**• Time resolution = 1.56 ns**

**Pixel Detector** *CERN PS - Timepix*



Multi-turn extraction showing transverse beamlets



filtering After filtering

**Beam loss electrons**

#### *ANIMMA2019*

#### *ESS Test with ions F. Benedetti et al.*

Test of Timepix with  $H_2^+$  ions Very sensitive to energy









#### IPM – Ionization Remnants

• For electron detection, ions must not produce secondary electrons





**Exermilab** 

#### IPM Examples









## Residual Gas Fluorescence

• Similar to beam-induced ionization, except less energy transferred

$$
N_2 + p \to (N_2^+)^* + e^- + p \to N_2^+ + \gamma + e^- + p
$$

 $Xe + p \rightarrow (Xe)^* + p \rightarrow Xe + \gamma + p$ 

- Movement of excited molecule before emission
	- Determined by lifetime of excited state and energy of molecule
- Changes origination position of beam interaction

 $\tau(N_2) = 60$  ns  $\tau(Xe) = 6$  ns Distance from *kT* motion  $N_2 = 25 \mu m$  Xe < 1  $\mu$ m







## Residual Gas Fluorescence

- Behavior with beam energy shown to follow dE/dx expections
- Signal relative to ionizations
	- Number of primary ionizations for  $N_2$ 
		- ∼20 in 2 cm of atmospheric pressure *F. Sauli, CERN 77-09*
	- Number of photons from  $N_2$ 
		- ∼1.2 in 2 cm of atmospheric pressure *M. Friend, 3rd IPM Workshop M. Plum et al., NIMA 492, 2002*
	- ∼16 times fewer photons than ion pairs
	- $4\pi$  angular collection of ions
	- 45-degree half-angle cone is only  $\sim \pi/2$
	- Total is factor of 100 fewer photons
- Use gas injection to offset small number of photons









#### Residual Gas Fluorescence

#### *GSI*

*F. Becker et al., DIPAC2007 S. Cao, IBIC2020*







Need significant increase in pressure  $\rightarrow$  simulations with Molflow

Molflow: Monte Carlo simulation for vacuum system









#### Gas Jets

• Sheet of high velocity gas molecules created instead of using residual gas





*JPARC*

*LINAC*

**Exermilab** 

# Gas Jets

Collects ions

*J. Kamiya, 3rd IPM Workshop*





Sheet generating chamber No skimmers

Gas sheet image



Diameter of Phospher screen<br>(used for scale calibration) Beam cross-sectional shape (interaction with gas sheet)

Beam trace (interaction with residual gas)



**Exermilab** 







#### Deflection of Probe Beam

• Determine the profile of a hadron beam by using the deflection of a probe beam





**Exermilab** 

#### Electron Beam Profiler







# Electron(Ion) Beam Profiler

*FNAL MI*

~10 ns bunch length



Pixels

*R. Thurman-Keup, IBIC2023*



- Discrete steps of electron beam
	- 25 ns sweep time too long
	- Electrons move through too rapidly and see the gaps between bunches
- Use low energy ions
	- Slow ion deflection averages bunch structure

*J. Bosser et al.,* 

*NIMA 484 (2002)*



Xe+ @ 2.72 keV

*CERN SPS*





# Photoionization of H- by Laser

• A photon with enough energy (1064 nm is sufficient) can ionize the 'loose' electron on the H- ion which has a binding energy of 0.75 eV

 $H^- + \gamma \rightarrow H^0 + e^-$ 

- Electron is collected via magnetic field and detector
- Laser is stepped through the beam to obtain profile
- Additionally,  $H^0$  can be detected downstream to obtain divergence and thus emittance
	- Beam must be bent by magnet to isolate the H<sup>0</sup>
- For laser pulse lengths < bunch length, can measure bunch length







## Photoionization of H- by Laser

• Number of ionizations for laser perpendicular to beam



Wavelength (nm) *Data from Broad and Reinhardt, Phys . Rev. A14 (1976)*

Bunch density Laser density

Lorentz-transformed laser wavelength

- For a 30 mJ, 10 ns laser pulse on a 30 ps bunch with  $1 \times 10^8$  ions
	- Expect a few percent of the beam to be ionized  $\rightarrow$  1 pC of H<sup>0</sup>/e<sup>-</sup> pairs
	- Laser is usually 1064 nm due to commercial availability
- Called a Laserwire





Horizontal scan

## Photoionization of H- by Laser





# **EF** Fermilab







#### Future?

- Pixel Detectors (already here!!)
- Quantum gas jets!!
	- N. Kumar, IPAC2021
	- Can make pencil beams

Atomic Sieve







## Further Reading

9th DITANET Workshop, CERN, 2013, <https://indico.cern.ch/event/229959/> 1st IPM Workshop, CERN, 2016, <https://indico.cern.ch/event/491615> 2nd IPM Workshop, GSI, 2017, <https://indico.gsi.de/event/5366/> 3rd IPM Workshop, JPARC, 2018, <https://conference-indico.kek.jp/event/55/> CERN BGI(IPM) website,<https://bgi.web.cern.ch/>

P. Forck, IPAC2010, TUZMH01 J. Marroncle et al., IBIC2023, WEP001 R. Connolly et al., BNL-102439-2013-TECH K. Satou, IBIC2019, TUPP020 S. Levasseur et al., IBIC2021, TUOA05 F. Benedetti et al., ANIMMA2019 K. Satou, IBIC2017, WE3AB2 J. Storey, IBIC2017, WE2AB5 R. Thurman-Keup, IBIC2017, WE3AB3 V. Shiltsev, NIMA 986 (2021) 164744 F. Becker et al., DIPAC2009, TUPB02 M. Plum et al., NIMA 492, 2002

F. Becker et al., DIPAC2007,MOO3A02 S. Cao et al., IBIC2020, WEPP34 M. Putignano and C.P. Welsch, NIMA 667 (2012) N. Kumar et al., Physica Medica 73 (2020) 173–178 O. Sedlacek, IBIC2023, WE3I01 J. Bosser et al., NIMA 484 (2002) W. Blokland and S. Cousineau, NAPAC2011, WEOCN2 R. Thurman-Keup et al., IBIC2023, WEP023 and WEP025 Y. Liu, NAPAC2011, WEOCN1 T. Hofmann, Phys. Rev. ST Accel. Beams 18, 122801 V. Scarpine, IBIC2021, TUPP25 N. Kumar, IPAC2021, TUPAB280 Y. Liu, IBIC2023, MO2I01